Search Notes			

Application/Control No.	Applicant(s)/Paten Reexamination	Applicant(s)/Patent under Reexamination	
10/709,932	OVERLINE, EUG	OVERLINE, EUGENE	
Examiner	Art Unit		
Wen-Ying P. Chen	2871		

SEARCHED			
Class	Subclass	Date	Examiner
349	11	9/20/2005	WPC WPC
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
key word search in US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB databases in EAST	9/20/2005	WPC UPC
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